

INTERFERENCE

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L36	1	((crosstalk or nois\$4)and magnitude and glitch and analyz\$6 and insert\$4 and extract\$4 and ratio and size and buffer and node).CLM;	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/03 11:01

	Type	L #	Hits	Search Text	DBs
1	BRS	L1	9	(crosstalk or nosi\$4) same glitch same buffer	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B
2	BRS	L2	88	(crosstalk or nosi\$4) same glitch	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B
3	BRS	L3	14	((crosstalk or nosi\$4) same glitch) and extract\$4 and layout	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B

	Type	L #	Hits	Search Text	DBs
4	BRS	L4	69	((crosstalk or nosi\$4) same insert\$4) and extract\$4 and layout	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B
5	BRS	L5	8	((crosstalk or nosi\$4) same insert\$4) and extract\$4 and layout and (tim\$4 near4 slack)	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B
6	BRS	L6	166	((crosstalk or nosi\$4) same insert\$4) and extract\$4 and ratio and size	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B

	Type	L #	Hits	Search Text	DBs
7	BRS	L7	15	((crosstalk or nosi\$4) same insert\$4) and extract\$4 and ratio and size and ("716"/\$.ccls. or "326"/\$.ccls.)	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B
8	BRS	L8	28	((crosstalk or nosi\$4) same insert\$4) and extract\$4 and ratio and size and CMOS	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B
9	BRS	L9	65	((crosstalk or nosi\$4) same insert\$4) and extract\$4 and ratio and size and magnitude	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B

	Type	L #	Hits	Search Text	DBs
10	BRS	L10	47	((crosstalk or nosi\$4) same insert\$4) and extract\$4 and ratio and size and magnitude and buffer	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B
11	BRS	L11	3	((crosstalk or nosi\$4) same insert\$4) and extract\$4 and ratio and size and magnitude and buffer and parametric	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B
12	BRS	L12	40	((crosstalk or nosi\$4) same insert\$4) and extract\$4 and ratio and size and magnitude and buffer and node	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B

	Type	L #	Hits	Search Text	DBs
13	BRS	L13	295	(crosstalk or nosi\$4) and insert\$4 and extract\$4 and ratio and size and magnitude and buffer and node	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB
14	BRS	L14	9	(crosstalk or nosi\$4) and insert\$4 and extract\$4 and ratio and size and magnitude and buffer and node and ("716"/\$.ccls. or "326"/\$.ccls.)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB
15	BRS	L15	14	((crosstalk or nosi\$4) same magnitude) and insert\$4 and extract\$4 and ratio and size and magnitude and buffer and node	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB

	Type	L #	Hits	Search Text	DBs
16	BRS	L16	53	((crosstalk or nosi\$4)and magnitude and glitch and analyz\$6 and insert\$4 and extract\$4 and ratio and size and magnitude and buffer and node)"CLM."	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B
17	BRS	L18	4	((crosstalk or nosi\$4)and magnitude and glitch and analyz\$6 and insert\$4 and extract\$4 and ratio and size and buffer and node) and ("716"/\$.ccls. or "326"/\$.ccls.)	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B
18	BRS	L19	1	((crosstalk or nosi\$4)and magnitude and glitch and analyz\$6 and insert\$4 and extract\$4 and ratio and size and buffer and node).CLM.	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TD B


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» Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

**1. Substrate coupling evaluation in BiCMOS technology**

Casalta, J.M.; Aragonés, X.; Rubio, A.;

Solid-State Circuits, IEEE Journal of

Volume 32, Issue 4, April 1997 Page(s):598 - 603

Digital Object Identifier 10.1109/4.563684

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